

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SONG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,859,254	02-2005	Kim et al.	349/190
*	B	US-6,914,641	07-2005	Choo et al.	349/38
*	C	US-5,838,314	11-1998	Neel et al.	725/8
*	D	US-5,919,606	07-1999	Kazlas et al.	430/321
*	E	US-5,963,689	10-1999	Hesselbom, Hjalmar	385/53
*	F	US-6,037,044	03-2000	Giri et al.	428/209
*	G	US-6,057,896	05-2000	Rho et al.	349/42
*	H	US-6,330,043	12-2001	Kikkawa et al.	349/43
*	I	US-6,414,729	07-2002	Akiyama et al.	349/38
*	J	US-6,597,415	07-2003	Rho et al.	349/42
*	K	US-6,707,511	03-2004	Kim et al.	349/38
*	L	US-6,794,228	09-2004	Kim, Hong-Jin	438/149
*	M	US-6,862,050	03-2005	Rho et al.	349/44

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
(X)	U	Je-Hsiung Lan et al., 'Planarization technology Of a Si:H TFTs for Am-LCDs' , July 1988, SPIE Vol. 3421, SPIE conference On Display Techologies II , Taipei, Taiwan, pages 170-182. (<i>already mailed 9/01/05 see EDAN</i>)
(X)	V	Phillip E. Garrou et al. , ' Stress-Buffer and Passivation Processes for SI and GaAs IC's and Passive Components Using Photosensitive BCB: Process Technology and Reliability Data ' IEEE Transactions on AdvancedPackaging , Vol. 22 No.3 August 1999, pages <i>already mailed 9/01/05 - See EDAN</i>)
(X)	W	M.J. Radler et al., " A2.4 : Cyclotene Advanced Electronics resins for High-Aperture AMLCD Applications " , 1996 , SID 96 Applications Digest pages 33-36 <i>already mailed 09/01/05 - See EDAN</i>
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/690,573 SONG ET AL.	
		Examiner	Art Unit	Page 2 of 2 Steven H. Rao 2814

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,780,871	07-1998	den Boer et al.	257/59
*	B	US-5,287,208	02-1994	Shimoto et al.	349/123
*	C	US-6,862,052	03-2005	Kim, Dong-Gyu	349/54
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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	P					
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	V	
	W	
	X	

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